

Application No. 10/020,707
Amendment dated February 25, 2004
Reply to Office action of January 16, 2004

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1 Claim 1 (currently amended): An electrical test probe tip for use with a
2 probing head, comprising:
- 3 (a) a conductive flexible coil having a first end and a second end;
- 4 (b) said first end for coupling with a device to be probed;
- 5 (c) a connector attached to said second end of said conductive flexible
6 coil with minimal overlap between said connector and said second
7 end of said flexible coil; and
- 8 (d) said connector for connecting to said probing head; and
- 9 ~~(e) — said conductive flexible coil at least partially extending beyond said~~
10 ~~probing head when said connector is connected to said probing~~
11 ~~head.~~

- 12
- 1 Claim 2 (previously presented): The electrical test probe tip of claim 1,
2 said connector being a connecting pin coupleable to said probing head.

- 3
- 1 Claim 3 (previously presented): The electrical test probe tip of claim 1,
2 said connector being a square pin coupleable to said probing head.

- 3
- 1 Claim 4 (withdrawn): The electrical test probe tip of claim 1, said
2 connector being in integral connection with said probing head.

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1 Claim 5 (original): The electrical test probe tip of claim 1, said flexible coil
2 having a longitudinal axis and a first diameter, said first diameter being substantially
3 equal throughout said longitudinal axis of said flexible coil.

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1 Claim 6 (withdrawn): The electrical test probe tip of claim 5, said first end
2 having a second diameter larger than said first diameter.

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1 Claim 7 (withdrawn): The electrical test probe tip of claim 1, said first end
2 further comprising a hook.

3

1 Claim 8 (withdrawn): The electrical test probe tip of claim 1, said first end
2 further comprising a foot.

3

1 Claim 9 (withdrawn): The electrical test probe tip of claim 1 further
2 comprising an exterior conductive sheath at least partially surrounding said conductive
3 flexible coil.

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1 Claim 10 (withdrawn): The electrical test probe tip of claim 1 further
2 comprising an exterior insulating sheath at least partially surrounding said conductive
3 flexible coil.

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1 Claim 11 (withdrawn): The electrical test probe tip of claim 1 further
2 comprising a conductor disposed at least partially through the axial center of said
3 conductive flexible coil.

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1 Claim 12 (withdrawn): The electrical test probe tip of claim 11, wherein
2 said conductor is made of a conductive elastomer.

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1 Claim 13 (currently amended): A multipurpose electrical test probe tip
2 ~~interconnectable with a probing head~~, comprising:

3 (a) a conductive flexible member and having a longitudinal length;

4 (b) said flexible member having a first end at a first end of said
5 longitudinal length and a second end at a second end of said
6 longitudinal length;

7 (c) said flexible member being substantially hollow at said first end;
8 and

9 (d) a connector;

10 (e) said connector being connected to said second end of said flexible
11 member;

12 (f) said flexible member being flexible along substantially the entire
13 longitudinal length of said flexible member when interconnected
14 with said connector. ~~first end of said conductive flexible member for~~
15 ~~securely flexibly coupling with a component to be probed so as to~~
16 ~~allow movement of said probing head.~~

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1 Claim 14 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, wherein said second end of said conductive flexible member is
3 interconnectable with said probing head.

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1 Claim 15 (withdrawn): The multipurpose electrical test probe tip of claim
2 14, wherein said second end of said conductive flexible member is integral with said
3 probing head.
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1 Claim 16 (original): The multipurpose electrical test probe tip of claim 14,
2 said second end of said conductive flexible member further comprising a connector
3 coupleable with said probing head.
4

1 Claim 17 (original): The multipurpose electrical test probe tip of claim 13,
2 said flexible member having a longitudinal axis and a first diameter, said first diameter
3 being substantially equal throughout said longitudinal axis of said flexible coil.
4

1 Claim 18 (withdrawn): The multipurpose electrical test probe tip of claim
2 17, said first end having a second diameter larger than said first diameter.
3

1 Claim 19 (withdrawn): The multipurpose electrical test probe tip of claim
2 13, said first end further comprising a hook.
3

1 Claim 20 (withdrawn): The multipurpose electrical test probe tip of claim
2 13, said first end further comprising a foot.
3

1 Claim 21 (withdrawn): The multipurpose electrical test probe tip of claim
2 13 ~~claim 4~~ further comprising an exterior conductive sheath at least partially surrounding
3 said conductive flexible member.
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1 Claim 22 (withdrawn): The multipurpose electrical test probe tip of claim
2 ~~13 claim-4~~ further comprising an exterior insulating sheath at least partially surrounding
3 said conductive flexible member.

1 Claim 23 (withdrawn): The multipurpose electrical test probe tip of claim
2 ~~13 claim-4~~ further comprising a conductor disposed at least partially through the axial
3 center of said conductive flexible member.

1 Claim 24 (withdrawn): A method for using a multipurpose electrical test
2 probe having a probing head, said method comprising the steps of:

- 3 (a) providing a flexible spring tip, said flexible spring tip having a
4 connector end connectable to said probing head and a flexible coil
5 contact end remote from said probing head;
6 (b) connecting said connector end to said probing head; and
7 (c) placing said contact end in flexible electrical contact with an
8 electrical component to be probed so as to permit movement of
9 said probing head.

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1 Claim 25 (cancelled):

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1 Claim 26 (cancelled):

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1 Claim 27 (cancelled):

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1 Claim 28 (previously presented): The electrical test probe tip of claim 1,
2 said conductive flexible coil being substantially hollow at said first end.
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1 Claim 29 (previously presented): The electrical test probe tip of claim 1,
2 said conductive flexible coil being substantially hollow.
3

1 Claim 30 (previously presented): The electrical test probe tip of claim 1,
2 said first end of said conductive flexible coil being suitable to receive a device to be
3 probed therein.
4

1 Claim 31 (previously presented): The electrical test probe tip of claim 1,
2 wherein said first end of said conductive flexible coil at least partially surrounds a device
3 to be probed.
4

1 Claim 32 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, said conductive flexible member being substantially hollow.
3

1 Claim 33 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, said first end of said conductive flexible member being suitable to receive a
3 component to be probed therein.
4

1 Claim 34 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, wherein said first end of said conductive flexible member at least partially
3 surrounds a component to be probed.
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1 Claim 35 (withdrawn): The electrical test probe tip of claim 1, said first
2 end of said flexible coil having at least one additional coupling mechanism extending
3 therefrom, said additional coupling mechanism selected from the group consisting of:

- 4 (a) an enlarged coil having a diameter larger than the diameter of said
5 flexible coil;
6 (b) a hook; and
7 (c) a foot.

8

1 Claim 36 (withdrawn): The electrical test probe tip of claim 13, said first
2 end of said flexible coil having at least one additional coupling mechanism extending
3 therefrom, said additional coupling mechanism selected from the group consisting of:

- 4 (a) an enlarged coil having a diameter larger than the diameter of said
5 flexible coil;
6 (b) a hook; and
7 (c) a foot.

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1 Claim 37 (cancelled):

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1 Claim 38 (cancelled):

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1 Claim 39 (new): An electrical test probe tip, comprising:

- 2 (a) a conductive flexible coil having a first end and a second end, said
3 first end opposite said second end;
4 (b) a connector;

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- 5 (c) said first end of said conductive flexible coil for coupling with a
6 device to be probed; and
- 7 (d) said connector attached to the extreme second end of said
8 conductive flexible coil with substantially no overlap between said
9 conductive flexible coil and said connector.

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1 Claim 40 (new): The electrical test probe tip of claim 39, said conductive
2 flexible coil having a longitudinal length, said conductive flexible coil being flexible along
3 substantially said entire longitudinal length of said conductive flexible coil when
4 interconnected with said connector.

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1 Claim 41 (new): A multipurpose electrical test probe tip interconnectable
2 with a probing head, comprising:

- 3 (a) a conductive flexible member and having a longitudinal length;
4 (d) a connector;
5 (b) said flexible member having a first end at a first end of said
6 longitudinal length and a second end at a second end of said
7 longitudinal length;
8 (c) said flexible member being substantially hollow at said first end;
9 (e) said connector being connected to said second end of said flexible
10 member;
11 (f) said flexible member being flexible along substantially the entire
12 longitudinal length of said flexible member when interconnected
13 with said connector.

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1 Claim 42 (new): The multipurpose electrical test probe tip of claim 41,
2 said connector attached to said second end of said conductive flexible member with
3 minimal overlap between said connector and said second end of said conductive
4 flexible member.

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1 Claim 43 (new): The multipurpose electrical test probe tip of claim 41,
2 said connector attached to the extreme end of said second end of said conductive
3 flexible member.

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